

Search Notes

Application/Control No.

10/777,134

Examiner

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Applicant(s)/Patent under
Reexamination

HAYAMIZU ET AL.

Art Unit

2182

SEARCHED

Class	Subclass	Date	Examiner
710	15-21	3/18/2006	CBS
710	62-74	3/18/2006	CBS
710	316-317	3/18/2006	CBS
345	156-184	3/18/2006	CBS
345	594	3/18/2006	CBS
708	139-146	3/18/2006	CBS

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
710	67	3/20/2006	CBS
708	139	3/20/2006	CBS
710	73,21	3/20/2006	CBS
345/168,173,594		3-20-06	CBS

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PLUS	3/18/2006	CBS
PALM (DOUPLE PATENTING)	3/18/2006	CBS
EAST (USPGPUG, USPAT, USOCR, EPO, JPO, DERWENT, IBMTDB)	3/18/2006	CBS